

Report No.: 오류! 참조 원본을 찾을 수 없습니다.015

ELECTROMAGNETIC COMPATIBILITY TEST REPORT

Test Report No.		RAPA23-O-021	
Anglinger	Name	Comfile Technology Inc.	
Applicant	Address	11-9, Gamasan-ro 27-gil, Guro-gu, Seoul, Republic of Korea	
Manufacturar	Name	Comfile Technology Inc.	
Manufacturer	Address	11-9, Gamasan-ro 27-gil, Guro-gu, Seoul, Republic of Korea	
Type of Equipme	ent	Touch Display Controller for Industrial	
Model Name		CPi-S101WR	
Multi Model Name		N/A	
Serial number		N/A	
Total page of Report		57pages (including this page)	
Test period		May 3, 2023 to June 1, 2023	
Issuing date of r	eport	June 5, 2023	

SUMMARY

The equipment complies with the standards; EN 55032:2015/A11:2020, EN 55035:2017/A11:2020 EN IEC 61000-3-2:2019/A1:2021+A1:2021 and EN 61000-3-3:2013/A2:2021

This test report contains only the result of a single test of the sample supplied for the examination. It is not a general valid assessment of the features of the respective products of the mass-production.

Prepared by:

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TCL of RAPA.

Reviewed by:

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TCL of RAPA.

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ISSUANCE OF TEST REPORT

Issuance date	test report number	purpose
June 5, 2023	RAPA23-O-021	Initial issuance
-	-	-

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1. APPLICANT AND MANUFACTURER INFORMATION

Applicant	Name	Comfile Technology Inc.	
Applicant	Address	11-9, Gamasan-ro 27-gil, Guro-gu, Seoul, Republic of Korea	
Manufacturar	Name	Comfile Technology Inc.	
Manufacturer	Address	11-9, Gamasan-ro 27-gil, Guro-gu, Seoul, Republic of Korea	
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2. TEST SUMMARY

2.1 Test standards and results

	STANDARDS	RESULTS
	Main Terminal Continuous Disturbance Voltage	See Note 1
EN 55032:2015/A11:2020	Conducted common mode disturbance at TEL ports	PASS
EN 33032.2013/A11.2020	Radiated Emission (Below 1 GHz)	PASS
	Radiated Emission (Above 1 GHz)	PASS
EN IEC 61000-3-2:2019/A1:2021	Harmonic Current Emission	See Note 1
EN 61000-3-3: 2013/A1:2021	EN 61000-3-3: 2013/A1:2021 Voltage Change, Voltage fluctuations and Flicker	
	Electrostatic discharge immunity	PASS
	Radio frequency electromagnetic fields	PASS
	Electrical fast transient/burst immunity	PASS
EN 55035:2017/A11:2020	Surge immunity	See Note 2
	Conducted disturbance induced by RF fields immunity	PASS
	Power frequency magnetic field immunity	See Note 3
	Voltage Dips and Short interruptions	See Note 1

NOTE 1: The equipment under test was DC mains power ports, so this test was not executed.

NOTE 2: The equipment under test was excluded from the test item because EUT doesn't have ports that can be connected directly to outdoor cable and cable longer than 3 m in length according to the manufacturer's specifications.

2.2 Additions, deviations, exclusions from standards

No additions, deviations or exclusions have been made from standards.

2.3 Purpose of the test

To determine whether the equipment under test fulfills the EMC requirements of the standards stated in section 2.1.

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NOTE 3: The equipment under test was not susceptible to magnetic fields, so this test was not executed.

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2.4 Test facilities

• Place of test : <u>Head office</u>

101 & B104, Anyang Megavalley, 268, Hagui-ro, Dongan-gu, Anyang-si, Gyeonggi-

do, Korea

Open Area Test Site

103, Anseok-dong, 138beon-gil, Hwaseong-si, Gyeonggi-do, Korea

(FCC OATS Registration Number: 931589)

(FCC Conformity Assessment Body, Registration Number: 608365)

(IC Company address code : 9355B) (RRA Designation Number : KR0027)

2.5 Criterion description

Criterion	Descriptions
А	The equipment shall continue to operate as intended without operator intervention. No degradation of performance, loss of function or change of operating state is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
В	During the application of the disturbance, degradation of performance is allowed. However, no unintended change of actual operating state or stored data is allowed to persist after the test. After the test, the equipment shall continue to operate as intended without operator intervention; no degradation of performance or loss of function is allowed, below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level (or the permissible performance loss), or recovery time, is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
С	Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. A reboot or re-start operation is allowed Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.



3. EUT (Equipment Under Test)

3.1 Identification of the EUT

Equipment : Touch Display Controller for Industrial

■ Model name : CPi-S101WR

• Multi model name : N/A

Brand name : Comfile Technology Inc.

Serial number : N/A

Manufacturer : Comfile Technology Inc.

3.2 Additional information about the EUT

The model CPi-S101WR (referred to as the EUT in this report) of ILOGICS INC.is Touch Display Controller for Industrial specification described herein was obtained from product data sheet or user's manual.

НМІ				
MCU	1.5 GHz 64-Bit Quad-Core ARM Cortex-A72 processor			
GPU	Broadcom VideoCore IV			
RAM	1 GB			
Storage	1 microSD Slot (Default: 8 GB)			
LCD	10.1 Inch (1024 x 600)			
Aspect Ratio	16:9			
Colors	162 K			
Contrast Ratio	600:1			
Brightness	250 cd/m2			
Touchscreen	Pressure-sensitive (Resistive Film Type)			
Housing	Flame retardant ABS IP65 Water-Resistant Front Panel			
Ethernet	100 Base-T (1 Port)			
Audio	Stereo audio output (ø3.5 Audio Jack)			
USB	USB 2.0 x 3 Port			
Serial	COM0 (RS232C)/COM1 (RS485)			
I2C	1 Port			
RTC	DS3231 (Battery rated for 5 years)			
GPIO	22 Port (includes ESD protection circuit) / 40-Pin Header socket			
Input Power	DC 12 V ~ DC 24 V			
Power Consumption	<10 W (0.8 A @12 V)			
Dimension	264(H)x170(V)x53(D) mm			
Weight	0.92 kg			
Operating Temperature	0 ℃ ~60 ℃			
Storage Temperature	-20 ℃ ~80 ℃			

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3.3 Peripheral equipment

It is defined as peripheral equipment needed for correct operation of the EUT but not considered as tested.

Model	Manufacturer	Description	Serial No.	
CPi-S101WR	Comfile Technology Inc.	Touch Display Controller for Industrial (EUT)	N/A	
HP 8570P B8Z36PA	HP	Laptop	N/A	
SeriesPPP012L-E	LITE-ON TECHNOLOGY (CHANGZHOU) CO., LTD.	Laptop Adapter	WBGTK0A1RZ9200	
GP-4303DU	EZ Digital Co., Ltd.	DC Power Supply	2100198	
N/A	N/A	Earphone	N/A	
32 GB	Sandisk	Micro SD card	N/A	
32 GB	Sandisk	USB memory 1	N/A	
32 GB	Sandisk	USB memory 2	N/A	
32 GB	Sandisk	USB memory 3	N/A	

3.4 Mode of operation during the test

By the applicant request, The EUT has maintained normal operation and full loaded traffic mode during the test. EUT Input power is DC 12, 24 V

3.5 Alternative type(s)/model(s); also covered by this test report

The followings are added model names and their differences.

Model Name	Differences	Tested
None	None	

NOTE1: Applicant asks only basic model to test. Therefore, testing laboratories just guarantee the unit which has been tested.



3.6 EUT cable description

Ports name		Shielded	Ferrite bead	Length (m)	Connected to
	DC IN	NO	NO	1.2	DC Power Supply
	COM0 RS232	NO	NO	1.5	Laptop
	COM1 RS485	NO	NO	1.2	Laptop
CPi-S101WR	I2C	NO	NO	0.2	EUT
(EUT)	USB 3 Port	-	NO	direct	EUT
	ETHERNET	NO	NO	3.0	Laptop
	μSD Card	-	NO	direct	EUT
	Audio Out	NO	NO	1.0	EUT
	DC IN	NO	NO	1.8	Laptop Adapter
Lonton	Serial 9 Pin	NO	NO	1.2	EUT
Laptop	RJ-45	NO	NO	3.0	EUT
	USB	NO	NO	1.5	EUT
DC Dower Supply	AC IN	NO	NO	1.5	AC MAIN
DC Power Supply	DC OUT	NO	NO	1.5	EUT

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4. EUT MODIFICATIONS

- None



5. EMISSION TESTS

5.1 Mains terminal continuous disturbance voltage

5.1.1 Operating environment

Temperature: -Humidity : -

5.1.2 Test set-up

The EUT was placed on a wooden table with 0.8 m height above the floor. The EUT was connected to AC power supply and the input power was supplied through a 50 Ω / 50 μ H ± 5 Ω Artificial Mains Network (AMN). The ground plane was electrically bonded to the reference ground system and all power lines were filtered from ambient.

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The test set-up photos are included in appendix I.

5.1.3 Measurement uncertainty

- Conducted emission, Quasi-peak detection: ± 3.46 dB
- Conducted emission, CISPR-Average detection: ± 3.14 dB

Measurement uncertainty is calculated in accordance with WECC 19-1990. The measurement uncertainty is given with a confidence of 95.45 % with the coverage factor, k = 2.

5.1.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
	ESCI7	Rohde & Schwarz	EMI Test Receiver	100938	Dec. 26, 2022
	ESH3-Z2	Rohde & Schwarz	Pulse Limiter	101631	Dec. 26, 2022
	ENV216	Rohde & Schwarz	LISN	101264	Jul. 04, 2022
	3825/2	EMCO	LISN	9004-1635	Jul. 04, 2022
	ES-SCAN	R&S	EMI Software	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.



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5.1.5 Test data

Test date : -Resolution bandwidth : 9 kHz

• Frequency range : 150 KHz ~ 30 MHz

Frequency (MHz)	Line	Quasi-peak			CISPR-Average		
		Emission level(dBµV)	Limits (dBµV)	Margin (dB)	Emission level(dBµV)	Limits (dBµV)	Margin (dB)
Not Applicable							

• Plots			

- This test was excepted because EUT uses DC power.

SeungSoo Kim / Assistant Manager

5.2 Conducted common mode disturbance at telecommunication ports

5.2.1 Operating environment

Temperature: 16.0 °CHumidity : 54.5 % R.H.

5.2.2 Test set-up

The EUT and other support equipment were placed on a wooden table, 0.8 m height above the floor. Telecommunication line for the EUT connected to the associated equipment through an Impedance Stabilization Network (ISN) which has a common mode termination impedance of 150 Ω to the telecommunication port under test. The ground plane was electrically bonded to the reference ground system and all power lines were filtered from ambient.

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The test set-up photos are included in appendix II.

5.2.3 Measurement uncertainty

- Conducted emission, Quasi-peak detection: ± 3.46 dB
- Conducted emission, CISPR-Average detection: ± 3.14 dB

Measurement uncertainty is calculated in accordance with WECC 19-1990. The measurement uncertainty is given with a confidence of 95 % with the coverage factor, k = 2.

5.2.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
\boxtimes	ESCI7	Rohde & Schwarz	EMI Test Receiver	100938	Dec. 26, 2022
\boxtimes	ESH3-Z2	Rohde & Schwarz	Pulse Limiter	101631	Dec. 26, 2022
\boxtimes	ENV216	Rohde & Schwarz	LISN	101264	Jul. 04, 2022
\boxtimes	3825/2	EMCO	LISN	9004-1635	Jul. 04, 2022
\boxtimes	CAT3 8158	SCHWARZBECK	ISN	8158-0031	Dec. 23, 2022
\boxtimes	CAT5 8158	SCHWARZBECK	ISN	8158-0047	Dec. 23, 2022
	CVP 9222 C	SCHWARZBECK	Capacitive Voltage Probe	00045	Jan. 06, 2023
\boxtimes	ES-SCAN	Rohde & Schwarz	EMI Software	N/A	N/A

Remark: All test equipment used is calibrated on a regular basis.

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5.2.5 Test data

■ Test date : May 31, 2023

• Resolution bandwidth : 9 kHz

• Frequency range : 0.15 MHz ~ 30 MHz

■ Test mode: 10 Mbps (DC 12 V)

_		Quasi-peak			CISPR-Average		
Frequency (MHz)	Port	Emission Level (dBµV)	Limits (dBµV)	Margin (dB)	Emission Level (dBµV)	Limits (dBµV)	Margin (dB)
0.17	RJ-45	41.69	95.96	54.27	39.64	82.96	43.32
0.48	RJ-45	46.62	87.37	40.75	43.46	74.37	30.91
1.02	RJ-45	50.96	87.00	36.04	48.16	74.00	25.84
6.70	RJ-45	57.59	87.00	29.41	52.44	74.00	21.56
18.24	RJ-45	68.64	87.00	18.36	65.26	74.00	8.74
23.13.	RJ-45	68.02	87.00	18.98	64.39	74.00	9.61

■ Test mode: 100 Mbps (DC 12 V)

_		Quasi-peak			CISPR-Average		
Frequency (MHz) Port		Emission Level (dBµV)	Limits (dBµV)	Margin (dB)	Emission Level (dBµV)	Limits (dBµV)	Margin (dB)
0.48	RJ-45	48.60	87.37	38.77	46.12	74.37	28.25
1.43	RJ-45	46.94	87.00	40.96	43.96	74.00	30.04
2.39	RJ-45	47.57	87.00	39.43	43.64	74.00	30.36
6.39	RJ-45	55.41	87.00	31.59	46.91	74.00	27.09
8.92	RJ-45	58.25	87.00	28.75	53.04	74.00	20.9
23.13	RJ-45	59.05	87.00	27.95	54.61	74.00	19.39



■ Test mode: 10 Mbps (DC 24 V)

Frequency		Quasi-peak			CISPR-Average		
(MHz)	Port	Emission Level (dBµV)	Limits (dBµV)	Margin (dB)	Emission Level (dBµV)	Limits (dBµV)	Margin (dB)
0.20	RJ-45	46.88	94.69	47.81	44.79	81.69	36.90
0.35	RJ-45	46.27	89.87	43.60	45.01	76.87	31.86
1.02	RJ-45	51.28	87.00	35.72	48.56	74.00	25.44
5.91	RJ-45	57.42	87.00	29.58	52.60	74.00	21.40
16.23	RJ-45	68.33	87.00	18.67	65.08	74.00	8.92
23.13	RJ-45	68.69	87.00	18.31	65.56	74.00	8.44

■ Test mode: 100 Mbps (DC 24 V)

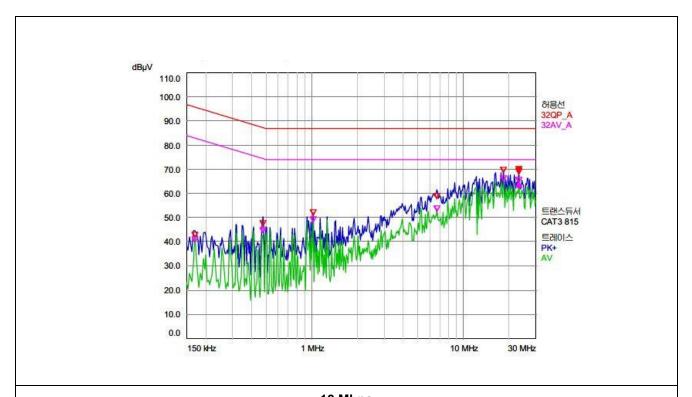
_		Quasi-peak			CISPR-Average		
Frequency (MHz)	Port	Emission Level (dBµV)	Limits (dBµV)	Margin (dB)	Emission Level (dBµV)	Limits (dBµV)	Margin (dB)
0.48	RJ-45	48.31	87.37	39.06	45.88	74.37	28.49
1.43	RJ-45	45.80	87.00	41.20	43.50	74.00	30.50
2.39	RJ-45	48.32	87.00	38.68	44.73	74.00	29.27
8.82	RJ-45	58.03	87.00	28.97	52.88	74.00	21.12
12.20	RJ-45	59.06	87.00	27.94	54.17	74.00	19.83
23.13	RJ-45	58.84	87.00	28.16	54.03	74.00	19.97

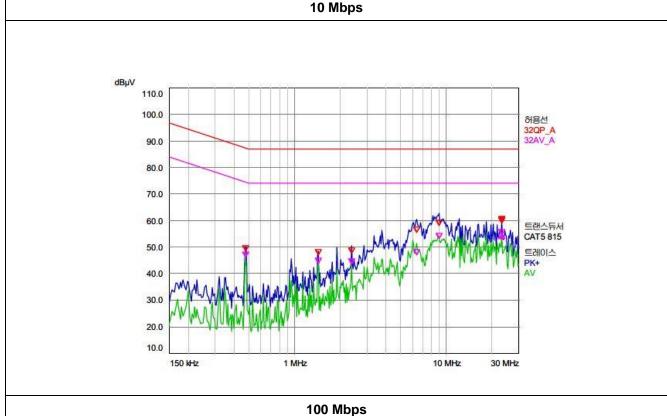
The equipment doesn't have wired network port, so this test was not executed

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■ Test mode: DC 12 V



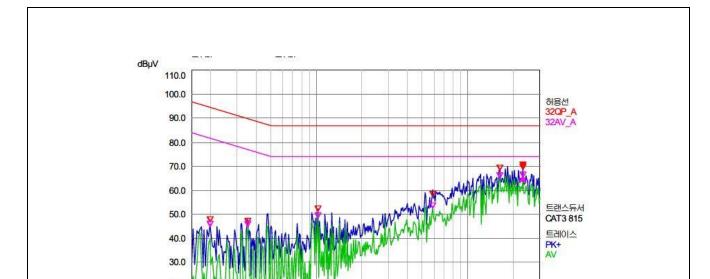


20.0 10.0 0.0

150 kHz



■ Test mode: DC 24 V



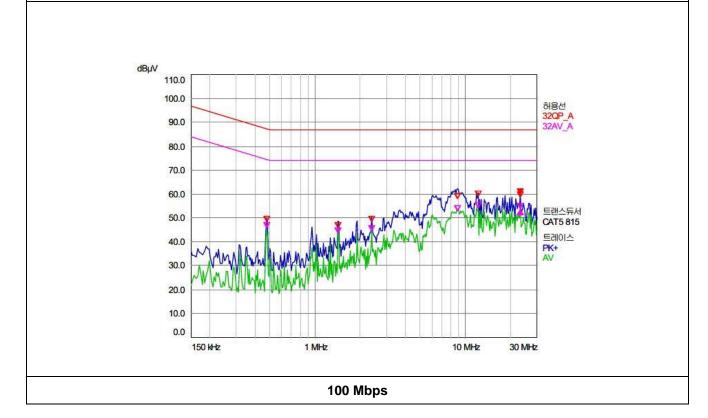
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10 MHz

30 MHz

1 MHz



5.3 Radiated electromagnetic field (Below 1 GHz)

5.3.1 Operating environment

Temperature: 23.7 °CHumidity : 52.1 % R.H.

5.3.2 Test set-up

The radiated emissions were measured at the 10 m Open Area Test Site. The EUT was placed on a wooden table with 0.8 meters height above the ground plane.

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The frequency spectrum from 30 MHz to 1 000 MHz was scanned and maximum emission levels at each frequency recorded. The table was rotated 360° and the antenna was varied in height between 1.0 m and 4.0 m in order to detect the maximum emission levels. This procedure was performed for both horizontal and vertical polarization of the receiving antenna.

The test set-up photos are included in appendix III.

5.3.3 Measurement uncertainty

• Radiated emission electric field intensity in the range of 30 MHz \sim 1 000 MHz, Quasi-peak detection: \pm 4.36 dB Measurement uncertainty is calculated in accordance with WECC 19-1990. The measurement uncertainty is given with a confidence of 95 % with the coverage factor, k = 2.

5.3.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
\boxtimes	ESS	R&S	EMI Test Receiver	833776/011	Jul. 04, 2022
\boxtimes	DS 1500 S-1t-O	Innco GmbH	Innco GmbH Turn Table		N/A
\boxtimes	MA4000-O	Innco GmbH	Antenna Mast	N/A	N/A
\boxtimes	CO 2000	Innco GmbH	Controller	N/A	N/A
\boxtimes	VULB 9168	SCHWARZBECK	Trilog-Broadband Antenna	9168-735	Nov. 17, 2021
\boxtimes	AMP 20-1000	INFINITECH	BROADBAND PRE-AMP	2013 05 0003	Dec. 22, 2022
	CMAD 1614	SCHWARZBECK	CMAD	00318	Jan. 05, 2023

Remark: All test equipment used is calibrated on the regular basis.

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5.3.5 Test data

Test date : May 22, 2023Resolution bandwidth : 120 kHz

• Frequency range : 30 MHz ~ 1 000 MHz

• Measurement distance : 10 m

■ Test Mode: DC 12 V Mode

Frequency (MHz)	Reading (dBµV)	ANT Pol. (H/V)	Ant. Height (m)	Angle (°)	Ant. Factor (dB/m)	Cable Loss +Amp (dB)	Emission Level (dBµV/m)	Limits (dBµV/m)	Margin (dB)
130.00	48.10	V	2.80	110.00	11.90	-33.57	26.43	40.00	-13.57
260.00	60.80	Н	4.00	250.00	12.14	-32.31	40.63	47.00	-6.37
325.01	52.10	V	2.70	390.00	13.90	-32.39	33.61	47.00	-13.39
390.01	58.10	Н	1.50	170.00	15.36	-32.75	40.71	47.00	-6.29
455.01	50.10	Н	2.00	300.00	17.06	-32.47	34.69	47.00	-12.31
500.00	49.10	Н	3.30	250.00	17.60	-32.09	34.61	47.00	-12.39

■ Test Mode: DC 24 V Mode

Frequency (MHz)	Reading (dBµV)	ANT Pol. (H/V)	Ant. Height (m)	Angle (°)	Ant. Factor (dB/m)	Cable Loss +Amp (dB)	Emission Level (dBµV/m)	Limits (dBµV/m)	Margin (dB)
130.00	48.20	٧	2.80	110.00	11.90	-33.57	26.53	40.00	-13.47
260.01	62.20	Н	4.00	240.00	12.14	-32.31	42.03	47.00	-4.97
390.01	52.50	I	1.50	170.00	15.36	-32.75	35.11	47.00	-11.89
455.01	57.40	Н	2.00	310.00	17.06	-32.47	41.99	47.00	-5.01
500.01	49.40	Н	3.30	250.00	17.60	-32.09	34.91	47.00	-12.09
550.01	35.40	V	1.80	80.00	18.40	-31.75	22.05	47.00	-24.95

Tabulated test data for Radiated Electromagnetic Field

Here, H = Horizontal, V = Vertical

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5.4 Radiated electromagnetic field (Above 1 GHz)

5.4.1 Operating environment

Temperature: 20.2 °CHumidity : 44.4 % R.H.

5.4.2 Test set-up

The radiated emissions were measured at the 3 m Anechoic Chamber. The EUT was placed on a wooden table with 0.8 meters height above the ground plane.

The frequency spectrum from 1 000 MHz to 6 000 MHz was scanned and maximum emission levels at each frequency recorded. The table was rotated 360° and the antenna was varied in height between 1.0 m and 2.0 m in order to detect the maximum emission levels. This procedure was performed for both horizontal and vertical polarization of the receiving antenna.

The test set-up photos are included in appendix IV.

5.4.3 Measurement uncertainty

- Radiated emission electric field intensity in the range of 1 000 MHz ~ 6 000 MHz, peak detection: ±4.80 dB
- Radiated emission electric field intensity in the range of 1 000 MHz ~ 6 000 MHz, CISPR-average: ± 4.72 dB

Measurement uncertainty is calculated in accordance with WECC 19-1990. The measurement uncertainty is given with a confidence of 95 % with the coverage factor, k = 2.

5.4.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
\boxtimes	FSV30	Rohde & Schwarz	Spectrum Analyze	101673	Dec. 21, 2022
\boxtimes	ALL1.5TT	Airlink Lab.	N/A	N/A	N/A
\boxtimes	ALL2.2MA	Airlink Lab.	N/A	N/A	N/A
\boxtimes	ALL-TMC- 2X-PG	Airlink Lab.	N/A	N/A	N/A
\boxtimes	Broadband Pre-AMP	Infinitech	Broadband Pre-AMP	2013 05 00002/1	Dec. 22, 2022
\boxtimes	BBHA-9120D	Schwarzbeck	Horn Antenna	395	Jun. 04, 2021
\boxtimes	RE32_V1_5	Airlink Lab.	RE Test System	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

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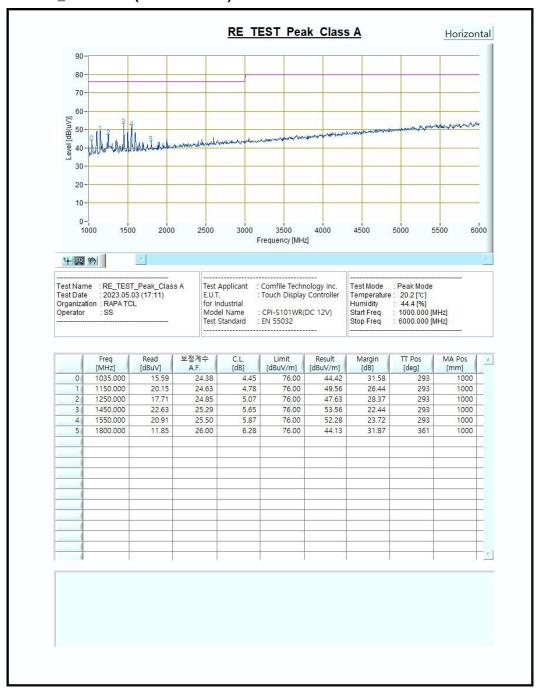
5.4.5 Test data

Test date : May 3, 2023Resolution bandwidth : 1 MHz

■ Frequency range : 1 000 MHz ~ 6 000 MHz

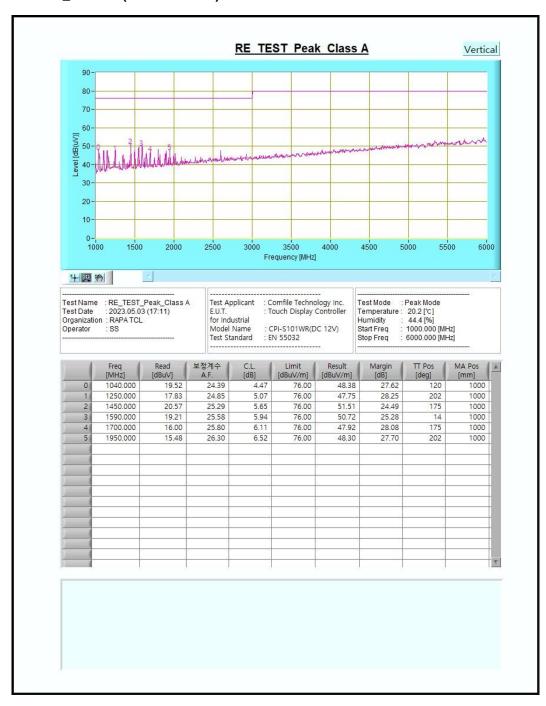
• Measurement distance : 3 m

Test mode: Peak_Horizontal (DC 12 V Mode)



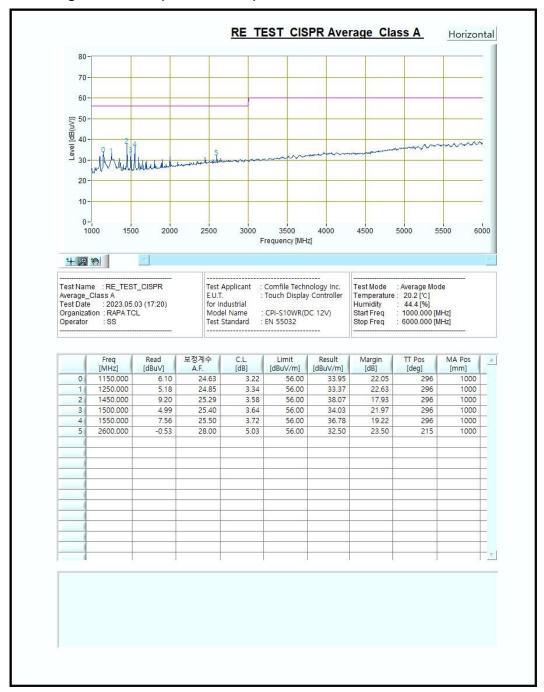


Test mode: Peak_Vertical (DC 12 V Mode)





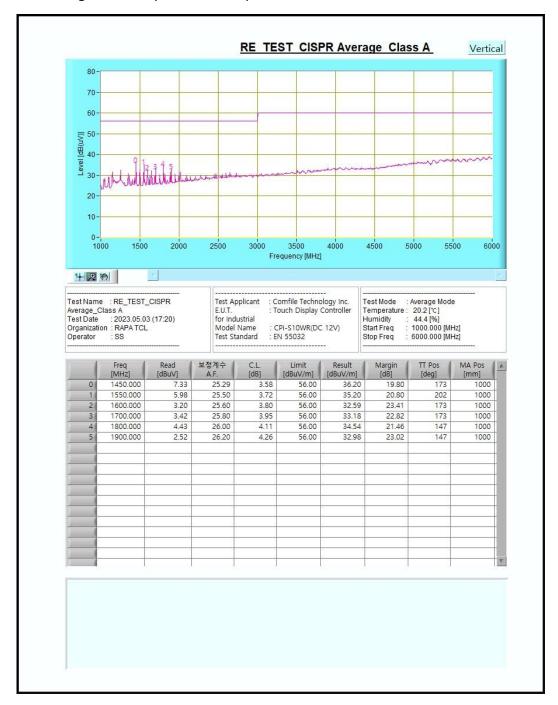
■ Test mode: Average_Horizontal (DC 12 V Mode)





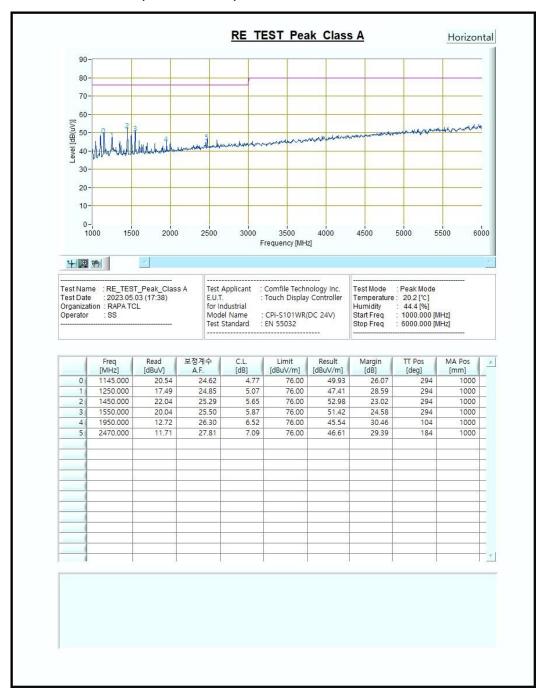
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Test mode: Average_Vertical (DC 12 V Mode)



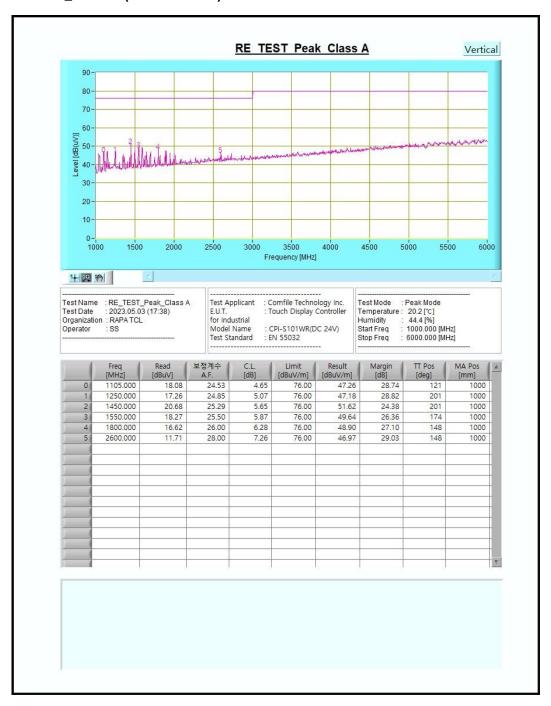


Test mode: Peak_Horizontal (DC 24 V Mode)



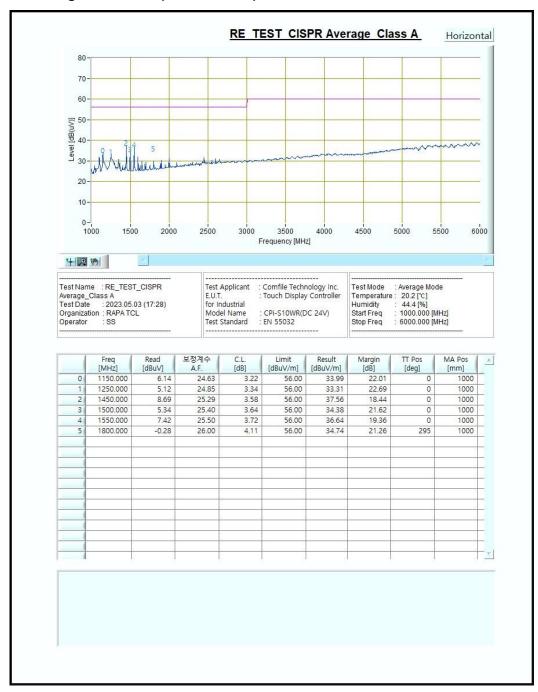


Test mode: Peak_Vertical (DC 24 V Mode)



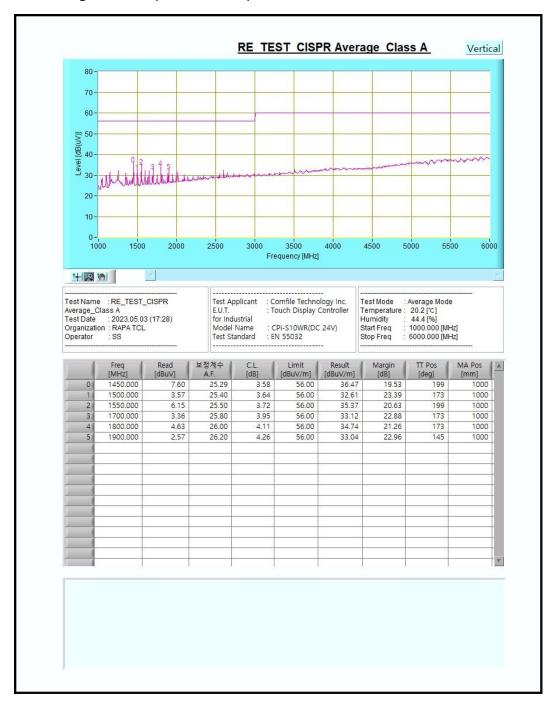


■ Test mode: Average_Horizontal (DC 24 V Mode)





Test mode: Average_Vertical (DC 24 V Mode)



5.5 Harmonic Current Emissions

5.5.1 Operating environment

Temperature: -Humidity : -

5.5.2 Test set-up

Harmonics of the fundamental current were measured up to 2 kHz using a universal power analyzer. The measurements were carried out under steady conditions and identical test conditions.

Before taking measurements, it is necessary for the EUT to decide which class the EUT fulfills into; A, B, C or D.

The test set-up photo is included in appendix V.

5.5.3 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
	DPA500N1	EM Test	Digital Power Analyzer	V0937105136	Dec. 27, 2022
	ACS500N3	EM Test	Universal Power Analyzer	V0937105137	N/A
	dpa.control	EM Test	The measurement and analysis software for Harmonics & Flicker	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

.5.4 Test data

- Test date : -Class : -Test result : -
- This test was excepted because EUT uses DC power

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5.6 Voltage changes, Voltage fluctuations and Flicker

5.6.1 Operating environment

Temperature: -Humidity : -

5.6.2 Test set-up

The voltage changes at the supply terminals were measured across the complex reference impedance $Z = (0.4 + j0.25) \Omega$. The short-term flicker values are measured during a time interval of 10 min. Dc (relative voltage change between two steady states) and D_{max}(maximum single voltage change) are measured over the reference impedance.

The test set-up photo is included in appendix V.

5.6.3 Measurement uncertainty

• The uncertainty of our equipment for flicker measurement: ± 5 %.

Measurement uncertainty is calculated in accordance with WECC 19-1990. The measurement uncertainty is given with a confidence of 95 % with the coverage factor, k = 2.

5.6.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
	DPA500N1	EM Test	Digital Power Analyzer	V0937105136	Dec. 27, 2022
	ACS500N3	EM Test	Universal Power Analyzer	V0937105137	N/A
	dpa.control	EM Test	The measurement and analysis software for Harmonics & Flicker	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

5.6.5 Test data

Test date : -Class : -Test result : -

- This test was excepted because EUT uses DC power

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6. IMMUNITY TESTS

6.1 Electrostatic discharge immunity test

The measurement of the Immunity against Electrostatic Discharge was performed in a shield room.

Test Location : Shielded Room (S121)

Date : June 1, 2023Here, S121 = Shield room number

6.1.1 Operating environment

Item	Measured	Recommended
Ambient temperature	15.5 °C	15 °C ~ 35 °C
Relative humidity	58.0 % R.H.	30 % R.H ~ 60 % R.H
Atmospheric pressure	101.2 kPa	86.0 kPa ~ 106.0 kPa

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6.1.2 Test set-up

The EUT and all peripheral equipment were placed on non-metallic support with 0.8 m height above a reference ground plane (RGP) and were put into operation according to the specified operating mode.

The test set-up photo is included in appendix VI.

6.1.3 Measurement uncertainty

It has been demonstrated that the ESD generator meets the specified requirements in the standard with at least 95 % confidence.

6.1.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
\boxtimes	ESS-2000	NOISEKEN	ESD Simulator	ESS0308043	Dec. 20, 2022
\boxtimes	TC-815P	NOISEKEN	ESD Gun	ESS0120522	Dec. 20, 2022

Remark: All test equipment used is calibrated on the regular basis.

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6.1.5 Test data

Test levels : Contact discharge 2 kV / 4 kV, Air discharge 2 kV / 4 kV / 8 kV

Number of discharges
 25 each pol. at each point for contact discharge, 10 each pol. at each

point for air discharge

Polarity : Positive / Negative

■ The EUT Position : Table Top

Required performance criterion: BTest result: A

Monitoring of the EUT
 The EUT was operated with all operating mode continuously during the test

■ Test mode : DC 12 V Mode, DC 24 V Mode

The test points of the EUT are each location on the surface touchable by hand (see test point in next page) and four sides of the EUT (through VCP and HCP).

The results of selected test points of the EUT are listed in the below table.

Point		Test level [± kV]	Pass / Fail	Description
(1)	Screw, Ethernet Port	2 / 4 (Contact)	Pass	
(1)	USB Port	2 / 4 (Contact)	Pass	
(2)	Frame (Non-Metal)	2 / 4 / 8 (Air)	Pass	There was no deviation from normal
(2)	Port (Power, RS232, RS485)	2 / 4 / 8 (Air)	Pass	operation condition.
(2)	I2C, GPIO Port	2 / 4 / 8 (Air)	Pass	
	HCP / VCP	4 (Contact)	Pass	

⁻ The static electricity discharges applied only front frame and display panel because back of product is only accessible under maintenance.

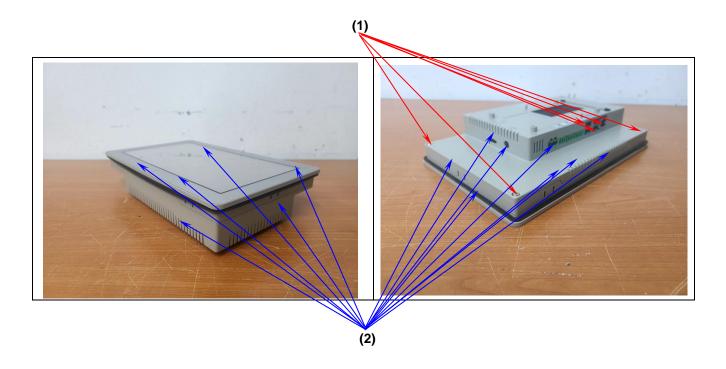
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6.1.6 ESD Test point table

	ESD Point	ESD Point Discharge voltage [± kV]	
(1)	Screw, Ethernet Port	2 / 4 (Contact)	Criterion A
(1)	USB Port	2 / 4 (Contact)	Criterion A
(2)	Frame (Non-Metal)	2 / 4 / 8 (Air)	Criterion A
(2) Power, RS232, RS485, I2C, GPIO Port		2 / 4 / 8 (Air)	Criterion A
	HCP / VCP	4 (Contact)	Criterion A



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6.2 Radiated RF-electromagnetic field immunity test

The measurement of the Immunity against Radiated RF-Electromagnetic Field was performed in an anechoic chamber.

Test location : Anechoic Chamber (S111)

■ Date : May 13, 2023

Here, S111 = Anechoic Chamber number

6.2.1 Operating environment

Ambient temperature : (21.6 ± 1.0) °C
 Humidity : (51.1 ± 2.0) % R.H.

6.2.2 Test set-up

The EUT and all peripheral equipment were placed on a non-metallic support 0.8 m above a reference ground plane (RGP) and were put into operation according to the specified operating mode.

The test set-up photo is included in appendix VII.

6.2.3 Measurement uncertainty

■ The measurement uncertainty: 2.22 V/m for 1 V/m, 3 V/m, 10 V/m.

Measurement uncertainty is calculated in accordance with WECC 19-1990. The measurement uncertainty is given with a confidence of 95%.

6.2.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
\boxtimes	SMBV100A	R&S	Signal Generator	263455	N/A
\boxtimes	E4419B	Agilent	EPM Series Power Meter	GB38410335	Dec 23, 2022
\boxtimes	E9300A	Agilent	Power Sensor	MY41497581	Dec 23, 2022
\boxtimes	E9300A	Agilent	Power Sensor	MY41497836	Dec 23, 2022
	ITRS-086KM2	Infinitech	Wide Band High Power Amplifier	2012 10 00001	Jul 05, 2022
\boxtimes	K9128	Airlink Lab	RS Antenna	N/A	-
\boxtimes	BBHA-9120D	Schwarzbeck	Horn Antenna	395	Jun 04, 2021
\boxtimes	TST-1000	TESTEK	Sound Acoustic Tester	150043	Jul 06, 2022
\boxtimes	CA111	BSWA TECH	Calibrator for Microphone	520042	Jul 07, 2022
\boxtimes	MPA261	BSWA TECH	Microphones	530025	Jul 07, 2022
	TIB-R1	TESTEK	Impedance Box	150030	Jul. 05, 2022
\boxtimes	IMS	KTI	EMS	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

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6.2.5 Test data

■ Test level : 3 V/m (AM 80 %, 1 kHz)

• Frequency range : 80 MHz ~ 1 000 MHz, 1.8 GHz, 2.6 GHz, 3.5 GHz, 5.0 GHz

Frequency step : 1 %Dwell time at each frequency : 3 s

Exposed side : Front / Rear / Left / RightPolarization of antenna : Horizontal / Vertical

The EUT position : Table Top
 Distance from antenna to EUT : 3 m
 Required performance criterion : A

Test result : Met criterion A

Monitoring of the EUT : The EUT was operated with all operating mode continuously during the test

■ Test mode : DC 12 V Mode, DC 24 V Mode

The results of test are listed in below table.

Freq. Range [MHz]	Ant. Pol.	Exposed side	Pass / Fail	Description
80 ~ 1 000	V	Left / Right / Front / Rear	Pass	
80 ~ 1 000	Н	Left / Right / Front / Rear	Pass	There was no deviation from normal
1 800, 2 600, 3 500, 5 000	V	Left / Right / Front / Rear	Pass	operation condition.
1 800, 2 600, 3 500, 5 000	Н	Left / Right / Front / Rear	Pass	

Here, H = Horizontal, V = Vertical

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6.3 Electrical fast transient/burst immunity test

The measurement of the Immunity Fast Transient/Burst was performed in a shield room.

Test location : Shielded Room (S121).

■ Date : May 30, 2023

6.3.1 Operating environment

Ambient temperature : 16.0 °C
Humidity : 55.0 % R.H.

6.3.2 Test set-up

The EUT was placed on non-metallic support with 0.1 m height above a reference ground plane (RGP) and was put into operation according to the specified operating mode. If the manufacturer provides a non-detachable supply cable more than 0.5 m long with the equipment, the excess length of this cable shall be folded to avoid a flat coil and situated at a distance of 0.1 m above the ground reference plane.

The test set-up photo is included in appendix VIII.

6.3.3 Measurement uncertainty

It has been demonstrated that the burst generator met the specified requirements in the standard with at least 95 % confidence.

6.3.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
\boxtimes	UCS 500N7	EM Test	Ultra Compact Generator	V937105138	Jul. 05, 2022
\boxtimes	HFK	EM Test	Capacitive Coupling Clamp	0709-26	Dec. 21, 2022
\boxtimes	iec.control	EM Test	Software for industrial and telecom testing	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

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6.3.5 Test data

■ Test level : 1 kV (AC power port), 0.5 kV (DC power port)

Burst frequency : 5 kHz

Polarity : Positive / Negative

Coupling methods : Signal line – Capacitive Coupling Clamp (CCC)

Lines for test
 Type of line & length
 Handlogue/digital data ports for EUT
 Unshielded above 3.0 m (RJ-45)

• The EUT-position : Table Top

Required performance criterion : B

Test result : Met criterion A

Monitoring of the EUT
 The EUT was operated with all operating mode continuously during the test

■ Test mode : DC 12 V Mode, DC 24 V Mode

The results of test are listed in below table.

Line for test	Coupling Method	Test level [± kV]	Pass / Fail	Description
Signal Cable RJ-45 (Ethernet)	ccc	0.5	Pass	There was no deviation from normal operation condition.

Here, for the AC mains, L = Hot, N = Neutral, PE = Protective Earth, for the DC-mains, L = Positive, N = Negative.

The equipment under test was excluded from the test item because EUT power cable less than 3 m in length according to the manufacturer's specifications

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6.4 Surge immunity test

The measurement of the Surge Transients immunity was performed in a shield room.

■ Test location : Shielded Room (S121).

• Date : -

6.4.1 Operating environment

Ambient temperature : -Humidity : -Atmospheric pressure : -

6.4.2 Test set-up

The EUT and all peripheral equipment were placed on a non-metallic support with 0.8 m height above a reference ground plane (RGP) and were put into operation according to the specified operating mode.

The test set-up photo is included in appendix IX.

6.4.3 Measurement uncertainty

It has been demonstrated that the surge generator meets the specified requirements in the standard with at least 95 % confidence.

6.4.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
	UCS 500N7	EM Test	Ultra Compact Generator	V0937105138	Jul. 05, 2022
	SP02	EM TEST	HV contacts	N/A	N/A
	iec.control	EM Test	Software for industrial and telecom testing	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

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6.4.5 Test data

Test level : 1.0 kV (Line-Line)
 Number of surge : 5 surges / polarity
 Polarity : Positive / Negative

Angle : 90° / 270°
 Repetition rate : 60 s
 Coupling methods : Lines for test : -

■ Type of line and length : Unshielded 0.5 m AC mains

• The EUT-position : Table Top

Required performance criterion : BTest result : -

Monitoring of the EUT
 The EUT was operated with all operating mode continuously during the test

■ Test mode : -

The results of test are listed in below table.

Line for test	Coupling Method	Test level [± kV]	Pass/ Fail	Description
-	-	-	-	There was no deviation from normal operating condition.

⁻ DC power port can't be connected directly to outdoor cables so this test excepted.

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6.5 Conducted disturbance induced by RF fields immunity

The measurement of the Immunity against Injection Current was performed in the Shield Room.

Test Location: Shielded Room (S121).

■ Date : May 30, 2023

6.5.1 Operating environment

Ambient temperature : (16.0 ± 1.0) °C
 Humidity : (55.0 ± 2.0) % R.H.

6.5.2 Test set-up

The EUT and all peripheral equipment were placed on a non-metallic support with 0.1 m height above a reference ground plane (RGP) and were put into operation according to the specified operating mode.

The test set-up photo is included in appendix X.

6.5.3 Measurement uncertainty- The measurement uncertainty: ± 0.17 V for 1.8 V, ± 0.50 V for 5.4 V and ± 1.70 V for 18 V.

Measurement uncertainty is calculated in accordance with WECC 19-1990. The measurement uncertainty is given with a confidence of 95 %.

6.5.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
\boxtimes	CWS 500N1	EM Test	Continuous Wave Simulator	V0937105141	Jul. 05, 2022
\boxtimes	5906 N-50-1	Huber + Suhner	Attenuator 6dB/75W	253452201	Dec. 22, 2022
\boxtimes	FCC-801-M2/M3-16A	FCC	CDN	091759	Jul. 04, 2022
	FCC-801-T2-RJ45	FCC	CDN	091757	Jul. 04, 2022
\boxtimes	FCC-801-T4-RJ45	FCC	CDN	091757	Jul. 04, 2022
	EM101	Liithi	EM Clamp	35941	Dec. 20, 2022
\boxtimes	M016	Schaffner	CDN	16678	Jul. 04, 2022
\boxtimes	TST-1000	TESTEK	Sound Acoustic Tester	150043	Jul 06, 2022
\boxtimes	CA111	BSWA TECH	Calibrator for Microphone	520042	Jul 07, 2022
\boxtimes	MPA261	BSWA TECH	Microphones	530025	Jul 07, 2022
	TIB-R1	TESTEK	Impedance Box	150030	Jul. 05, 2022
\boxtimes	icd.control	EM Test	Software for conducted immunity from DC to 1 GHZ	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

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6.5.5 Test data

Test level : 3 V, 3 to 1 V, 1 V (AM 80 %, 1 kHz)
 Frequency range : 0.15~10 MHz, 10~30 MHz, 30~80 MHz

Frequency step : 1 %Dwell time at each frequency : 3 s

Coupling methods : Signal line – Capacitive Coupling Clamp (CDN),

Lines for test
 Type of line & length
 Handlogue/digital data ports for EUT
 Unshielded above 3.0 m (RJ-45)

• EUT-position : Table Top

Required performance criterion: A

Test result : Met criterion A

Monitoring of the EUT : The EUT was operated with all operating mode continuously during the test

■ Test mode : DC 12 V Mode, DC 24 V Mode

The results of test are listed in below table.

Freq. Range [MHz]	Coupling Method	Line for test	Test level [V]	Pass/ Fail	Description
0.15~10 10~30 30~80	CDN(T4)	Signal line (RJ45 port)	3 3 to 1 1	Pass	There was no deviation from normal operation condition.

The equipment under test was excluded from the test item because EUT power cable less than 3 m in length according to the manufacturer's specifications

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6.6 Main supply voltage Dips and Short interruptions immunity test

The measurement of the Voltage Dips and Interruptions Immunity was performed in a shield room.

■ Test location : Shielded Room (S101).

• Date : -

6.6.1 Operating environment

Ambient temperature : -Humidity : -Atmospheric pressure : -

6.6.2 Test set-up

The EUT and all local support equipment were placed on a non-metallic support with 0.8 m height above a reference ground plane (RGP) and were put into operation according to the specified operating mode.

The test set-up photo is included in appendix XI.

6.6.3 Measurement uncertainty

It has been demonstrated that the voltage dips and interruptions generator meets the specified requirements in the standard with at least 95 % confidence.

6.6.4 Test equipment used

Use	Model Number	Manufacturer	Description	Serial Number	Last Calibration
	UCS 500 N	EM Test	Ultra Compact Generator	V0937105138	Jul. 05, 2022
	MV2616	EM Test	Motorized VARIAC	V0937105140	N/A
	iec.control	EM Test	Software for industrial and telecom testing	N/A	N/A

Remark: All test equipment used is calibrated on the regular basis.

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6.6.5 Test data

Nominal Mains Voltage (V_{NOM}) : 230 Vac

Level of Reduction (dip)
 Level of Interruptions
 200 ms at 30 % of V_{NOM}
 10 ms at 100 % of V_{NOM}

No. of dips/interruption : 3Interval : 10 s

■ Type of line & length : Unshielded 0.5 m AC mains of the EUT

The EUT-position : Table Top
 Required performance criterion : B and C

Test result :Monitoring of the EUT :Test mode :-

The results of test are listed in below table.

Test	Reduction	Duration In time	Pass /	Perfor Crite	mance erion	Notes
	/% Ot \/\	(period)	Fail	Criteria	Result	
Valtage dine	> 95	0.5	Door	В		3 interrupts with 10 sec
Voltage dips	30	25	Pass	С	-	interval between each
Voltage Interruptions	> 95	250	Pass	С	-	test

Performance Criterion Results

Here,

A = Normal performance within the specification limits.

B = Temporary degradation or loss of function or performance which is self-recoverable.

C = Temporary degradation or loss of function of performance which requires operator intervention or system reset.

- This test was excepted because EUT uses DC power.

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APPENDIX I - TEST SET-UP PHOTOS: Mains terminal disturbance voltage					
		Not App	licable		
		N. d. A.			
		Not App	incable		

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APPENDIX II - TEST SET-UP PHOTOS: Conducted common mode disturbance at TEL ports



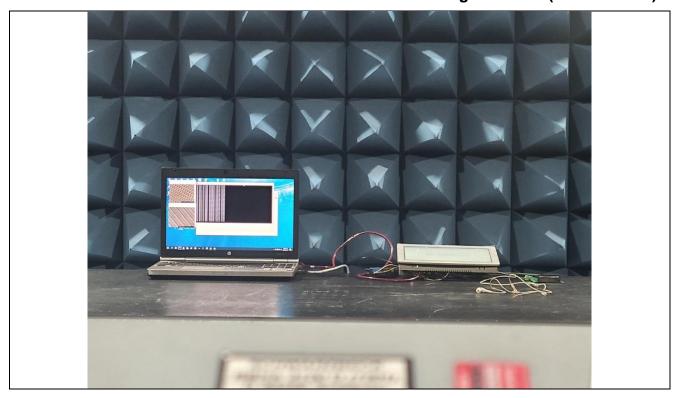
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APPENDIX III - TEST SET-UP PHOTOS: Radiated electromagnetic field (Below 1 GHz)





APPENDIX IV - TEST SET-UP PHOTOS: Radiated electromagnetic field (Above 1 GHz)



APPENDIX V - TEST SET-UP PHOTO: Harmonics & voltage fluctuations on AC mains **Not Applicable** APPENDIX V - TEST SET-UP PHOTO: Voltage changes, Voltage fluctuations and Flicker **Not Applicable**

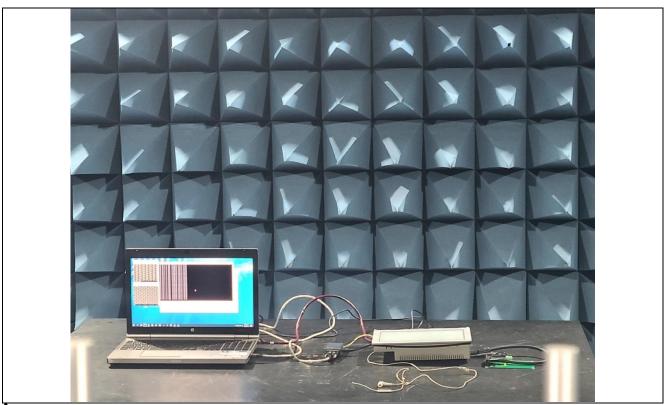


APPENDIX VI - TEST SET-UP PHOTO: Electrostatic discharge immunity

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APPENDIX VII - TEST SET-UP PHOTO: Radiated frequency electromagnetic field



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APPENDIX VIII - TEST SET-UP PHOTO: Electrical fast transient/burst immunity

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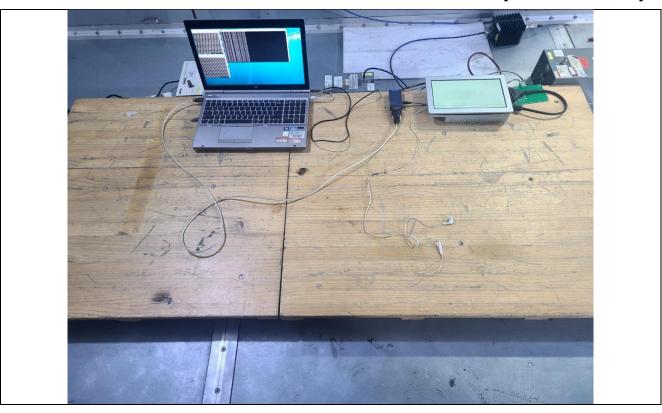
APPENDIX IX - TEST SET-UP PHOTO: Surge immunity

Not Applicable



APPENDIX X - TEST SET-UP PHOTO: Conducted disturbance induced by RF fields Immunity

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APPENDIX XI - TEST SET-UP PHOTO: Voltage Dips and Short interruptions

Not Applicable



APPENDIX XII - PHOTOGRAPHS: Internal and External appearances





















